

Source	Background yield variation	Signal yield variation
Electron identification and isolation	2.7%	2.6%
Integrated luminosity	2.5%	2.5%
Jet energy scale	2.1–2.4%	0.1–0.3%
Jet Pb tagging (heavy-flavour jets)	2.3%	2.0%
PDFs	1.0%	0.5%
Pileup	0.3–0.9%	0.7–1.3%
Pb tagging (light-flavour jets)	0.7–0.8%	< 0.1%
Muon identification	0.5%	0.4%
Jet energy resolution	0.2%	0.2%
Trigger efficiency	0.1–0.3%	0.1–0.3%
Muon isolation	0.2%	0.1%
Affecting only $t\bar{t}$ (31.8% of the total bkg.)		
$\mu_R$ and $\mu_F$ scales	12.2–12.3%	
$t\bar{t}$ cross section	5.3%	
Affecting only Drell-Yan (64.5% of the total bkg.)		
$\mu_R$ and $\mu_F$ scales	9.6%	
Drell-Yan cross-section	4.9%	
Drell-Yan shape uncertainty	2.1–2.2%	
Simulated sample size	0.5–1.3%	
Affecting only VV (1.1% of the total bkg.)		
$\mu_R$ and $\mu_F$ scales	4.3–4.8%	
Affecting only signal		
$\mu_R$ and $\mu_F$ scales	1.8%	